

<b>Notice of References Cited</b>	Application/Control No. 10/747,620	Applicant(s)/Patent Under Reexamination HAN, JAE WON	
	Examiner Kin-Chan Chen	Art Unit 1765	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-2004/0092110	05-2004	Sato et al.	438/689
	B	US-2003/0201538	10-2003	Lee et al.	257/751
	C	US-6,808,617	10-2004	Sato et al.	205/640
	D	US-6,881,318	04-2005	Hey et al.	205/87
	E	US-6,790,776	09-2004	Ding et al.	438/685
	F	US-6,610,596	08-2003	Lee et al.	438/653
	G	US-6,399,479	06-2002	Chen et al.	438/628
	H	US-2003/0022493	01-2003	Jiang et al.	438/687
	I	US-6,472,023	10-2002	Wu et al.	427/430.1
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	X	

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